

PALM INTRANET

Day : Wednesday

Date: 6/25/2003

Time: 14:05:11

Inventor Name Search Result

Your Search was:

Last Name = KUND

First Name = MICHAEL

*Inventor
Search
Pr
09/93646*

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<u>10195598</u>	Not Issued	030	07/11/2002	TEST METHOD AND TEST DEVICE FOR ELECTRONIC MEMORIES	KUND, MICHAEL
<u>10164770</u>	Not Issued	030	06/07/2002	DEVICE FOR AND METHOD OF EXAMINING THE SIGNAL PERFORMANCE OF SEMICONDUCTOR CIRCUITS	KUND, MICHAEL
<u>10000691</u>	Not Issued	071	11/15/2001	CONFIGURATION AND METHOD FOR INCREASING THE RETENTION TIME AND THE STORAGE SECURITY IN A FERROELECTRIC OR FERROMAGNETIC SEMICONDUCTOR MEMORY	KUND, MICHAEL
<u>09931686</u>	Not Issued	071	08/16/2001	APPARATUS FOR THE AUTOMATED TESTING, CALIBRATION AND CHARACTERIZATION OF TEST ADAPTERS	KUND, MICHAEL
<u>09705599</u>	Not Issued	083	11/03/2000	NEEDLE-CARD ADJUSTING DEVICE FOR PLANARIZING NEEDLE SETS ON A NEEDLE CARD	KUND, MICHAEL
<u>09642734</u>	<u>6256243</u>	150	08/17/2000	TEST CIRCUIT FOR TESTING A DIGITAL SEMICONDUCTOR CIRCUIT CONFIGURATION	KUND, MICHAEL
<u>09313422</u>	<u>6359457</u>	150	05/17/1999	METHOD OF HOLDING A WAFER AND TESTING THE INTEGRATED CIRCUITS ON THE WAFER	KUND, MICHAEL
<u>09138416</u>	<u>6184524</u>	150	08/24/1998	AUTOMATED SET UP OF	KUNDMANN,

<u>09138416</u>	<u>6184524</u>	150	08/24/1998	AUTOMATED SET UP OF AN ENERGY FILTERING TRANSMISSION ELECTRON MICROSCOPE	KUNDMANN , MICHAEL KARL
<u>08684973</u>	<u>5798524</u>	150	08/07/1996	AUTOMATED ADJUSTMENT OF AN ENERGY FILTERING TRANSMISSION ELECTRON MICROSCOPE	KUNDMANN , MICHAEL K.

Inventor Search Completed: No Records to Display.

	Last Name	First Name
Search Another: Inventor	<input type="text" value="KUND"/>	<input type="text" value="MICHAEL"/>
	<input type="button" value="Search"/>	

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Day : Wednesday

Date: 6/25/2003

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PALM INTRANET**Inventor Name Search Result**

Your Search was:

Last Name = APPEN

First Name = STEPHAN

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<u>09931686</u>	Not Issued	071	08/16/2001	APPARATUS FOR THE AUTOMATED TESTING, CALIBRATION AND CHARACTERIZATION OF TEST ADAPTERS	APPEN, STEPHAN

Inventor Search Completed: No Records to Display.**Search Another:
Inventor****Last Name**

APPEN

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STEPHAN

Search

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Day : Wednesday

Date: 6/25/2003

Time: 13:59:25

 PALM INTRANET**Inventor Name Search Result**

Your Search was:

Last Name = HUBNER

First Name = MICHAEL

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<u>10247575</u>	Not Issued	030	09/19/2002	METHOD FOR REWIRING PADS IN A WAFER-LEVEL PACKAGE	HUBNER, MICHAEL
<u>10105590</u>	Not Issued	030	03/25/2002	METHOD FOR RELEASABLE CONTACT-CONNECTION OF A PLURALITY OF INTEGRATED SEMICONDUCTOR MODULES ON A WAFER	HUBNER, MICHAEL
<u>10010504</u>	Not Issued	041	12/05/2001	TEST CONFIGURATION AND TEST METHOD FOR TESTING A PLURALITY OF INTEGRATED CIRCUITS IN PARALLEL	HUBNER, MICHAEL
<u>09931686</u>	Not Issued	071	08/16/2001	APPARATUS FOR THE AUTOMATED TESTING, CALIBRATION AND CHARACTERIZATION OF TEST ADAPTERS	HUBNER, MICHAEL

Inventor Search Completed: No Records to Display.

	Last Name	First Name
Search Another:	<input type="text" value="HUBNER"/>	<input type="text" value="MICHAEL"/>
Inventor	<input type="button" value="Search"/>	

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L Number	Hits	Search Text	DB	Time stamp
-	1950	324/158.1.ccls.	USPAT; US-PGPUB	2003/06/25 16:00
-	2674	324/754-758.ccls.	USPAT; US-PGPUB	2003/02/06 12:55
-	292	324/158.1.ccls. and 324/754-758.ccls.	USPAT; US-PGPUB	2003/02/06 12:55
-	2	(324/158.1.ccls. and 324/754-758.ccls.) and step\$ adj motor	USPAT; US-PGPUB	2003/02/06 12:56
-	2	(324/158.1.ccls. and 324/754-758.ccls.) and step\$ adj motor	USPAT; US-PGPUB	2003/02/06 12:56
-	1	"20020030485"	USPAT; US-PGPUB	2003/02/07 15:11
-	1	"20020030480"	USPAT; US-PGPUB	2003/02/07 15:11
-	84	paresh.xa.	USPAT; US-PGPUB	2003/06/25 13:43
-	0	6411079.URPN.	USPAT	2003/06/25 13:49
-	4	("4417204" "4820975" "5177528" "5525912").PN.	USPAT	2003/06/25 13:49
-	1	anjan.xa. and nishikawa.in.	USPAT; US-PGPUB	2003/06/25 14:00
-	0	6356093.URPN.	USPAT	2003/06/25 13:55
-	5	("4677474" "4820975" "4934064" "4985676" "5644245").PN.	USPAT	2003/06/25 13:55
-	230	hubner.in.	USPAT; US-PGPUB	2003/06/25 14:00
-	0	(michael adj hubner).in.	USPAT; US-PGPUB	2003/06/25 14:01
-	0	michael adj hubner	USPAT; US-PGPUB	2003/06/25 14:08
-	4	((("6256243") or ("6359457") or ("6184524") or ("5798524"))).PN.	USPAT; US-PGPUB	2003/06/25 14:08
-	2	(test adj head and adjust\$5 near2 pin).clm.	USPAT; US-PGPUB	2003/06/25 14:13
-	3	test adj head and adjust\$5 near2 pin	EPO; JPO; DERWENT; IBM_TDB	2003/06/25 14:15
-	17	4589815.URPN.	USPAT	2003/06/25 14:18
-	1842	324/754.ccls.	USPAT; US-PGPUB	2003/06/25 14:30
-	351	324/754.ccls. and pin and adjust\$5	USPAT; US-PGPUB	2003/06/25 14:30
-	1449	324/754.ccls.	EPO; JPO; DERWENT; IBM_TDB	2003/06/25 14:30
-	7	324/754.ccls. and pin and adjust\$5	EPO; JPO; DERWENT; IBM_TDB	2003/06/25 14:30
-	434	324/754.ccls. and pin and adjust\$5	USPAT; US-PGPUB	2003/06/25 14:38
-	184	324/754.ccls. and (pin probe) near2 adjust\$5	USPAT; US-PGPUB	2003/06/25 15:28
-	2142	324/754,761.ccls.	USPAT; US-PGPUB	2003/06/25 15:28
-	205	324/754,761.ccls. and adjust\$5 near2 (probe pin)	USPAT; US-PGPUB	2003/06/25 15:29
-	59	324/754,761.ccls. and adjust\$5 adj (probe pin)	USPAT; US-PGPUB	2003/06/25 15:29
-	2	((("4471298") or ("4904934"))).PN.	USPAT; US-PGPUB	2003/06/25 16:19
-	52	testing adj probe adj card	USPAT; US-PGPUB	2003/06/25 16:20
-	64	testing adj probe adj card	USPAT; US-PGPUB	2003/06/25 16:21
-	32	(testing adj probe adj card) and adjust\$5	USPAT; US-PGPUB	2003/06/25 16:21